

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination 09/963,788 FREUND ET AL.	
		Examiner	Art Unit Yelena G. Gakh, Ph.D.	1743 Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-2003/0109056	06-2003	Vossmeyer et al.	436/169
	C	US-			
	D	US-			
	E	US-			
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	J	US-			
	K	US-			
	L	US-			
	M	US-			

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	V	Wohltjen et al. "Colloidal Metal-Insulator-Metal Ensemble Chemiresistor Sensor", Anal. Chem., 1998, v. 70, No. 14, pp. 2856-2859
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.